## **Model 4121B**

### **Gated Integrator**



#### **FEATURES**

- 1 ns minimum gate width
- 80 kHz max trigger rate
- Linear or Exponential averaging
- Input offset control
- Normal and Baseline sampling modes
- Built-in trigger generator

#### **APPLICATIONS**

- Pulsed laser experiments
- Phosphorescence decay time studies
- Precision signal sampling

#### DESCRIPTION

This module is an ideal component for building boxcar averager systems. It includes a wide bandwidth variable gain AC/DC coupled input amplifier with offset adjustment and a high speed sampling gate with variable width and delay controls. It operates in normal or baseline sampling mode and features a switch-selected choice of how many samples are included in the averaging process. Separate outputs for the average and last sample taken are also provided. A gate monitor supplies a synchronized gate output pulse for application to an oscilloscope trigger or for referencing associated processing electronics. Trigger input is ECL or TTL or can be derived from the module's own adjustable trigger generator.

The module is packaged in a 2-unit wide NIM format and as such requires a suitable NIM rack and power supply to operate. The simplest single-channel system can therefore be produced with one model 4121B module and a suitable NIM rack and power supply (such as the **SIGNAL RECOVERY** model 4006 or 4001A/4002D. The addition of a second model 4121B and a model 4161A Display/ADC and control module provides a dual channel system with the added capability of allowing the transfer of output data to a computer for external analysis. Further modules can be added to increase the overall number of channels.

The unit can also be used with the model 9650A to build swept-gate waveform recovery boxcar systems, all controlled via either the Acquire data acquisition software or a LabVIEW program using the free LabVIEW driver.

Sensitivity

±20 mV to ±2 V in

< 10 ns

#### **Specifications**

General

			,		
	Single-channel gated in	tegrator module		1-2-5 sequence	
	mounted in NIM enclose	ure with adjustable	Coupling	AC/DC	
sensitivity, offset, gatewidth and output			Impedance		
	averager. Manual contro	ols.	DC only	$50~\Omega$ // $10~pF$	
			DC or AC	1 MΩ // 30 pF	
Analog gate delay generator with manual or DC			Maximum Safe Input		
	voltage control.		50 Ω Input	±5 V	
			1 MΩ Input	±100 V	
Measurement Modes On receipt of an external trigger, the instrument waits for the preset gate delay and then integrates the voltage present at its input for the preset gate width. On completion a DC voltage representing this integral is provided at the Last Sample Output connector and in addition fed forward into an analog integrator stage.			Offset	±10 × FS; non-	
				removable	
			Overload Indicator	LED	
			Overload Level	Input (signal plus	
				noise) > 1.1 × FS	
			Overload Recovery	Recovers after 1	
				sample for	
				×10 overload	
			Gain Drift	0.5% /°C, gate width	
Signal Channel				> 30 ns;	
	Mode	Normal or Baseline		1.0% /°C, gate width	

Sampling

DC Drift (referred to input)		Trigger Source		LSO Droop Rate	< 0.2% FS/s
	0.2%/°C, gate width > 20 ns;	Internal	0.5 Hz to 40 kHz selectable with range	Averager Droop Rate	When there are no triggers the droop rate
	1.0%/°C, gate width		switches 0.5, 5, 50,		is < 0.001% per
<b>5</b>	< 20 ns		500, 5000, off. Vernier		minute for 10k
Bandwidth			is 10× range.		samples
50 Ω input	DC to 450 MHz	External		Outputs	
1 MΩ DC input	DC to 100 MHz	ECL	Positive edge,	Average Out	$\pm 10$ V FS with 50 $\Omega$
1 MΩ AC input	1.5 Hz to 100 MHz		5 ns min pulse width		output impedance and
Signal Risetime			with termination of		capable of driving
50 Ω input	2 ns; 20% to 80%		50 $\Omega$ to -2 V; -5 V to		2 kΩ load
1 MΩ input	10 ns; 20% to 80%		+10 V pk-pk safe	Last Sample Out	±10 V FS
	from 50 $\Omega$ source.		input.	Gate Monitor	$0.3 \text{ V}$ into $50 \Omega$ to
		TTL	Negative edge,		ground. Marker pulse-
Sampler and Timing			20 ns min pulse width;		width equals gate
Gate Width			-5 V to +10 V safe		width. Position is
•	3-10 sequence, switch		input.		within 5 ns from actual
selectable with a c	ontinuously variable ×1	Max. Trigger Rate	80 kHz		gate
to ×5 multiplier		Trigger Indicator	LED lights when unit	Trigger	TTL
Sample Correlation	Less than 0.5% of		is triggered	Baseline Output	TTL output line that
	the sample output	Trigger Generator			toggles with each
	due to trigger t	Output	BNC TTL out on rear		trigger to indicate
	remains at trigger		panel active in all		whether next sample
	t + 1		trigger modes.		is signal or baseline
Gate Delay			Polarity set by jumper.		value.
Input	0 to 10 V DC varies	Frequency ranges	0.5, 5, 50, 500 Hz,	General	
	delay by 0.5% to		5 kHz and off with	Power Requirements	
	100% of range		vernier to overlap		+24 V at 200 mA;
	setting		ranges.		-24 V at 150 mA
Max delay	3 ns to 300 ns in a	Baseline Input	TTL line to indicate		+12 V at 300 mA;
	1-3-10 sequence plus		whether sample is		-12 V at 590 mA
	user options, which		signal or baseline		+6 V at 160 mA;
	give 10 µs (default),		value.		-6 V at 630 mA
	and 1 µs, 100 µs,			Dimensions	
	1 ms or 3 ms by	Analog Output Averag	er	Height	8¾" (222 mm)
	capacitor change.	Mode .	Linear or Exponential	Width	2¾" (70 mm)
		Samples Averaged	1, 3, 10, 30, 100, 300,	Depth	9¾" (248 mm)

# Why should you choose **SIGNAL RECOVERY** products?

Nodel 4121B Gated Integrator				
SIGNAL RECOVERY Product Features	Benefit to you			
Higher maximum sensitivity	Sensitivity settings on 4121B are for a full 10 V output, not the 1 V of competing units, allowing you to measure smaller signals			
High input bandwidth	Signals are less distorted before being sampled			
◆ 1 ns minimum gate width	Isolate narrower features more easily. In scanned gate work obtain finer resolution of peaks			
Built-in trigger generator	Use to trigger your experiment			
Linear or exponential averaging	Linear averaging means that every sample contributes equally to the output			
Baseline Out output	Will directly drive one of our light choppers for automatic baseline subtraction			
Faster Triggering	80 kHz max trigger rate allows acquisition up to 4 times faster than competing instruments			
Excellent reset of integrator between triggers	Ensures that each sample is essentially independent of previous samples			